

# **Maximum Ratings** (@ $T_A = +25^{\circ}C$ , unless otherwise specified.)

Characteristic			Symbol	Value	Unit
Source-Source Voltage			Vsss	12	V
Gate-Source Voltage			Vgss	±8	V
Continuous Source Current (Note 5) V <sub>GS</sub> = 4.5V	Steady State	$T_A = +25$ °C $T_A = +70$ °C	Is	24.4 19.6	Α
Continuous Source Current (Note 5) V <sub>GS</sub> = 2.5V	Steady State	T <sub>A</sub> = +25°C T <sub>A</sub> = +70°C	Is	16.4 13.1	Α
Pulsed Source Current (Note 6)			Ism	100	Α

### **Thermal Characteristics**

Characteristic	Symbol	Value	Unit
Power Dissipation (Note 7)	P <sub>D</sub>	1.10	W
Thermal Resistance, Junction to Ambient @T <sub>A</sub> = +25°C (Note 7)	$R_{\theta JA}$	114.1	°C/W
Power Dissipation (Note 5)	PD	2.47	W
Thermal Resistance, Junction to Ambient @T <sub>A</sub> = +25°C (Note 5)	R <sub>θJA</sub>	50.7	°C/W
Operating and Storage Temperature Range	TJ, TSTG	-55 to +150	°C

# **Electrical Characteristics** (@TA = +25°C, unless otherwise specified.)

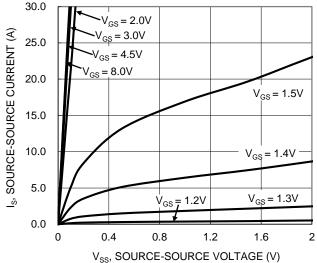
		1	1	1	ı		
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 8)							
Source-Source Breakdown Voltage	BVsss	12		_	V	$V_{GS} = 0V$ , $I_{S} = 1mA$	
Zero Gate Voltage Drain Current T <sub>J</sub> = +25°C	Isss	_	_	1	μA	Vss = 9.6V, Vgs = 0V	
Gate-Source Leakage	loos	_		±10	μΑ	$V_{GS} = \pm 8V$ , $V_{SS} = 0V$	
Gate-Source Leakage	Igss		_	±1.0	μΑ	$V_{GS} = \pm 5V$ , $V_{SS} = 0V$	
ON CHARACTERISTICS (Note 8)							
Gate Threshold Voltage	Vgs(TH)	0.35	8.0	1.4	V	Vss = 10V, Is = 1.41mA	
		1.5	2.27	2.75	mΩ	V <sub>G</sub> S = 4.5V, I <sub>S</sub> = 6A	
Static Source-Source On-Resistance	D	1.6	2.36	2.85		$V_{GS} = 3.8V, I_{S} = 6A$	
Static Source-Source On-Resistance	Rss(on)	1.7	2.54	3.95		V <sub>GS</sub> = 3.1V, I <sub>S</sub> = 6A	
		1.9	2.9	6.1		V <sub>G</sub> S = 2.5V, I <sub>S</sub> = 6A	
Diode Forward Voltage	Vss	_	0.69	1.2	V	V <sub>G</sub> S = 0V, I <sub>S</sub> = 6A	
DYNAMIC CHARACTERISTICS (Note 9)							
Input Capacitance	Ciss	_	3062	4593		Vss = 10V, Vgs = 0V, f = 1kHz	
Output Capacitance	Coss	_	758	1137	pF		
Reverse Transfer Capacitance	Crss	_	198	297		I = IKIIZ	
Total Gate Charge	Qg	_	45.7	68.6		Vss = 8V, Vgs = 4V, Is = 6A	
Gate-Source Charge	Q <sub>gs</sub>	_	8.3	12.5	nC		
Gate-Drain Charge	Qgd	_	16.0	24.0	IIC		
Gate Charge at V <sub>TH</sub>	Q <sub>g(th)</sub>	_	4.5	6.8			
Turn-On Delay Time	t <sub>D(ON)</sub>	_	1005	1508		Vss = 8V, Vgs = 4V,	
Turn-On Rise Time	tR	_	2186	3279	200		
Turn-Off Delay Time	tD(OFF)	_	2643	3965	ns	Is = 6A	
Turn-Off Fall Time	tF	_	4193	6290			

Notes:

- Device mounted on FR-4 material with 1-inch² (6.45-cm²), 2-oz. (0.071-mm thick) Cu.
   Repetitive rating, pulse width limited by junction temperature.
   Device mounted on FR-4 PCB with minimum recommended pad layout, single sided.

- 8. Short duration pulse test used to minimize self-heating effect.
- 9. Guaranteed by design. Not subject to production testing.





V<sub>SS</sub>, SOURCE-SOURCE VOLTAGE (V) Figure 1. Typical Output Characteristic

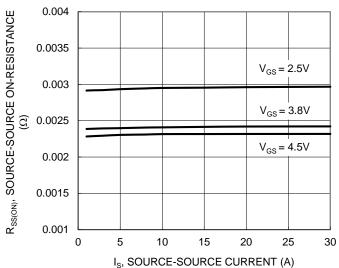


Figure 3. Typical On-Resistance vs. Source Current and Gate Voltage

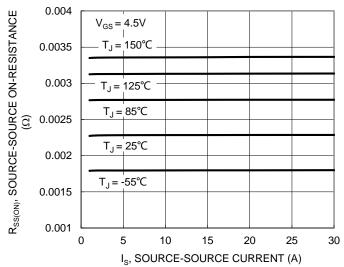
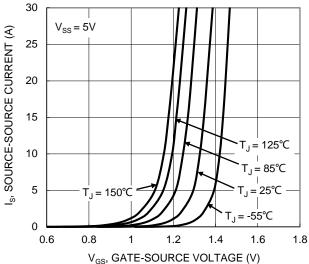


Figure 5. Typical On-Resistance vs. Source Current and Junction Temperature



V<sub>GS</sub>, GATE-SOURCE VOLTAGE (V)
Figure 2. Typical Transfer Characteristic

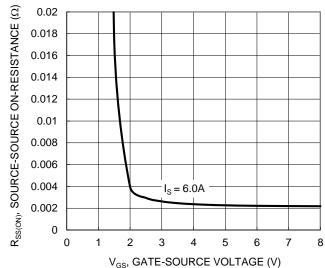


Figure 4. Typical Transfer Characteristic

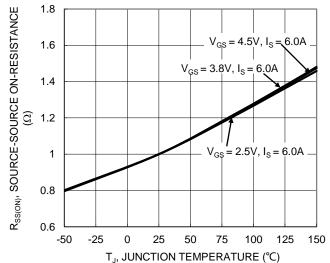


Figure 6. On-Resistance Variation with Junction Temperature



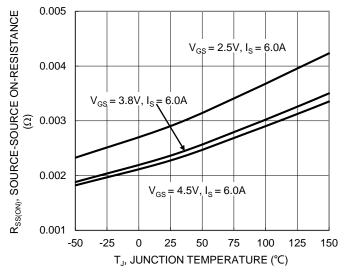
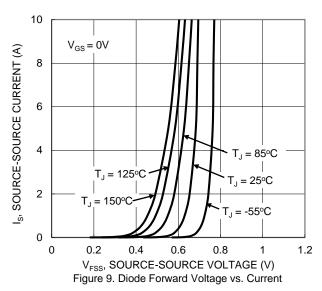
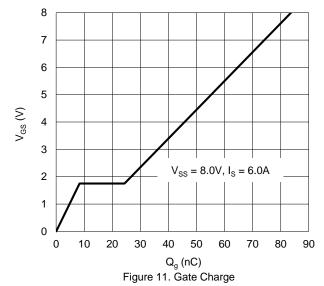


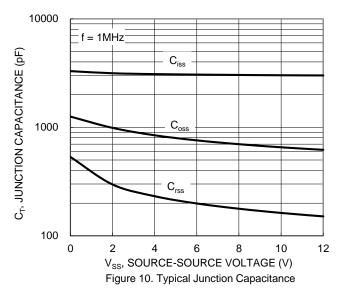
Figure 7. On-Resistance Variation with Junction Temperature





1.2  $V_{GS(TH)}$ , GATE THRESHOLD VOLTAGE (V) 1  $I_S = 1mA$ 8.0  $I_{S} = 250 \mu A$ 0.6 0.4 0.2 75 125 150 -50 -25 25 50 100 T<sub>.</sub>, JUNCTION TEMPERATURE (°C)

Figure 8. Gate Threshold Variation vs. Junction Temperature



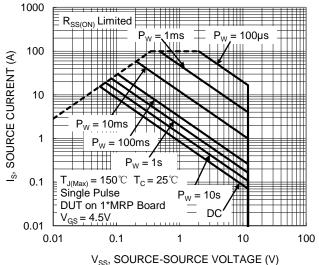


Figure 12. SOA, Safe Operation Area



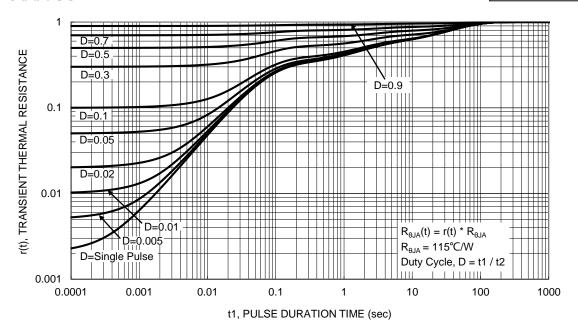


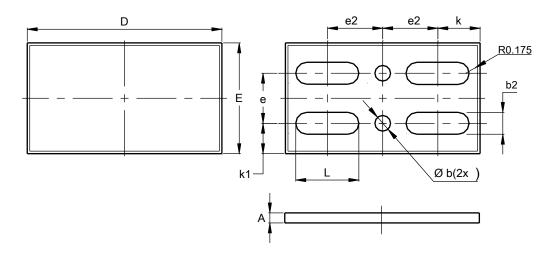
Figure 13. Transient Thermal Resistance



### **Package Outline Dimensions**

Please see http://www.diodes.com/package-outlines.html for the latest version.

### X4-DSN3118-6

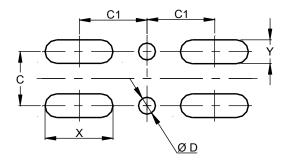


X4-DSN3118-6					
Dim	Min	Max	Тур		
Α	0.09	0.16	0.11		
b			0.25		
b2	0.32	0.38	0.35		
D	3.00	3.10	3.05		
Е	1.72	1.82	1.77		
е			0.800		
e2			0.878		
k			0.648		
k1			0.485		
L	0.975	1.035	1.005		
All Dimensions in mm					

## **Suggested Pad Layout**

Please see http://www.diodes.com/package-outlines.html for the latest version.

### X4-DSN3118-6



Dimensions	Value (in mm)			
С	0.800			
C1	0.878			
D	0.250			
Х	1.005			
Y	0.350			



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